

SEMICAPS 1100

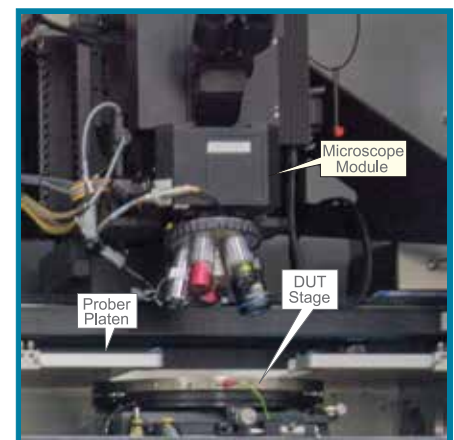
UPRIGHT ANALYTICAL SYSTEM

For
Your
Laboratory



Features

- For backside and frontside analysis of wafers, wafer parts and packaged devices
- Ultra-stable system compatible for probing FIB pads
- Compatible with third-party probe stations, probe cards and manipulators
- High resolution stage with 0.5 μm repeatability
- Aplanatic Refractive Solid Immersion Lens (ARSIL) option, currently probing 3nm nodes
- CAD interface option
- Analysis Methodologies include a combination of:
 - Laser Timing Probe (LTP)
 - Scanning Optical Microscopy (SOM) with best sensitivity for
 - static analysis: TIVA, OBIRCH
 - dynamic analysis: LADA, SDL
 - Photon Emission Microscopy (PEM) with various options for the InGaAs or Si-CCD camera
 - Thermal Microscopy (THM)



300 mm Probe Station

SEMICAPS Pte Ltd

A Company of SEMICAPS Corporation Group

Email: sales@semicaps.com <https://www.semicaps.com>

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Excellence In Innovation